## Sushanta Bordoloi

List of Publications by Year in descending order

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1937685 1872680 11 37 4 6 citations h-index g-index papers 13 13 13 25 docs citations times ranked citing authors all docs

| #  | Article  | IF  | CITATIONS |
|----|--|-----|-----------|
| 1  | A study on modeling and simulation of Multiple- Gate MOSFETs. Journal of Physics: Conference Series, 2016, 759, 012093.  | 0.4 | 10        |
| 2  | Numerical Simulation of Enhanced-Reliability Filleted-Gate AlGaN/GaN HEMT. Journal of Electronic Materials, 2020, 49, 2018-2031.   | 2.2 | 8         |
| 3  | Access Region Stack Engineering for Mitigation of Degradation in AlGaN/GaN HEMTs With Field Plate. IEEE Transactions on Device and Materials Reliability, 2022, 22, 73-84.             | 2.0 | 6         |
| 4  | Estimation of coulombic efficiency of lead acid battery for range determination of electric vehicle., 2015,,.  |     | 5         |
| 5  | Introspection Into Reliability Aspects in AlGaN/GaN HEMTs With Gate Geometry Modification. IEEE Access, 2021, 9, 99828-99841.  | 4.2 | 4         |
| 6  | Realization of multi-configurable logic gate behaviour on fluorescence switching signalling of naphthalene diimide congeners. RSC Advances, 2021, 11, 35274-35279.                     | 3.6 | 2         |
| 7  | FEM Based Device Simulator for High Voltage Devices. Communications in Computer and Information Science, 2017, , 127-135.  | 0.5 | 1         |
| 8  | Numerical analysis of the Impact of Gate Geometry variations on the Reliability of AlGaN/GaN HEMT. , 2021, , .   |     | 1         |
| 9  | Current Collapse Reduction Technique Using N-Doped Buffer Layer into the Bulk Region of a Gate Injection Transistor. , 2019, , .   |     | 0         |
| 10 | Investigation of Electric Field Profile and associated parameters with Embedded Metal Layer in Field Plate AlGaN/GaN HEMTs. Journal of Physics: Conference Series, 2022, 2236, 012005. | 0.4 | 0         |
| 11 | On-board Health Prognosis of Lithium-Ion Battery Based on the Estimation of Internal Resistance<br>Under Resistive and Inductive Loading Conditions. , 2022, , .                       |     | 0         |